

Notice of References Cited

Application/Control No.

10/577,919

Applicant(s)/Patent Under
Reexamination
LEE ET AL.

Examiner

MARCOS BATISTA

Art Unit

2617

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0115464 A1	08-2002	Hwang et al.	455/522
	B	US-			
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	D	US-			
	E	US-			
	F	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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